# FAIRCHILD

SEMICONDUCTOR

# 74F20 Dual 4-Input NAND Gate

### **General Description**

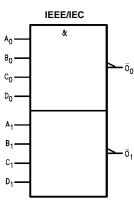
This device contains two independent gates, each of which performs the logic NAND function.

## **Ordering Code:**

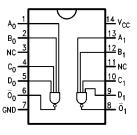
Order Number	Package Number	Package Description
74F20SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
74F20SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F20PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### Logic Symbol



# **Connection Diagram**



# **Unit Loading/Fan Out**

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
Pin Names	Description	HIGH/LOW Output		
$A_n, B_n, C_n, D_n$	Inputs	1.0/1.0	20 µA/-0.6 mA	
Ōn	Outputs	50/33.3	–1 mA/20 mA	

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74F20

#### Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with $V_{CC} = 0V$ )	
Standard Output	–0.5V to V <sub>CC</sub>
3-STATE Output	-0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated $I_{OL}$ (mA)

#### **Recommended Operating** Conditions

Free Air Ambient Temperature Supply Voltage

 $0^{\circ}C$  to  $+70^{\circ}C$ +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device -0.5V to  $V_{CC}$  may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

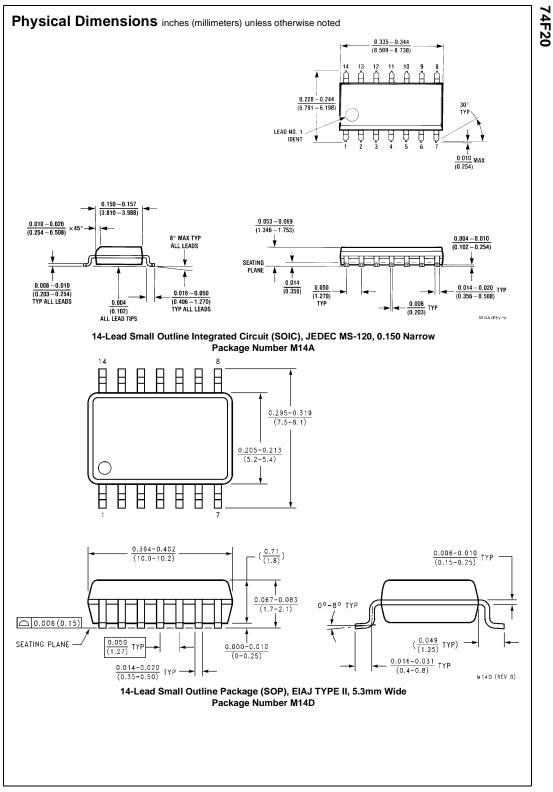
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

# **DC Electrical Characteristics**

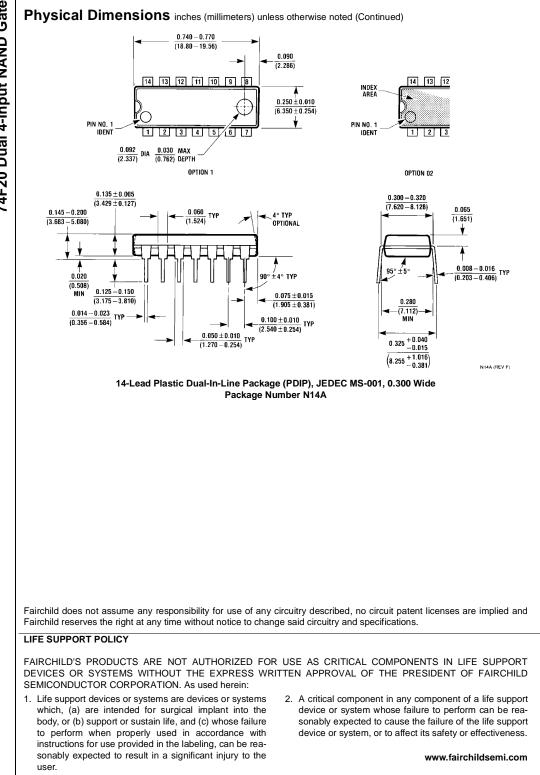
Symbol	Parameter Input HIGH Voltage		Min	Тур	Мах	Units	Vcc	Conditions		
VIH			2.0			V		Recognized as a HIGH Signal		
VIL	Input LOW Voltage				0.8	V		Recognized as a LOW Signal		
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA		
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5			V	Min	I <sub>OH</sub> = -1 mA		
	Voltage	5% $V_{CC}$	2.7					$I_{OH} = -1 \text{ mA}$		
V <sub>OL</sub>	Output LOW	10% V <sub>CC</sub>			0.5	v	Min	1 20 m 4		
	Voltage				0.5	v		I <sub>OL</sub> = 20 mA		
IIH	Input HIGH				5.0	μA	Max	V <sub>IN</sub> = 2.7V		
	Current				5.0	μΑ	IVIAX			
511	Input HIGH Current				7.0	μΑ	Max	V <sub>IN</sub> = 7.0V		
	Breakdown Test				7.0			$v_{IN} = 7.0v$		
I <sub>CEX</sub>	Output HIGH				50	A	Max			
	Leakage Current				50	μA	IVIAX	$V_{OUT} = V_{CC}$		
V <sub>ID</sub> Inp	Input Leakage		4.75	1		V	0.0	I <sub>ID</sub> = 1.9 μA		
	Test		4.75			v	0.0	All other pins grounded		
I <sub>OD</sub>	Output Leakage				3.75		0.0	V <sub>IOD</sub> = 150 mV		
	Circuit Current				3.75	μA		All other pins grounded		
IIL	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$		
los	Output Short-Circuit Current		-60		-150	mA	Max	V <sub>OUT</sub> = 0V		
I <sub>CCH</sub>	Power Supply Current			0.9	1.4	mA	Max	V <sub>O</sub> = HIGH		
I <sub>CCL</sub>	Power Supply Current			3.4	5.1	mA	Max	$V_{O} = LOW$		

### **AC Electrical Characteristics**

Symbol	Parameter	T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50 pF			$T_{A} = -55^{\circ} \text{ to } +125^{\circ}\text{C}$ $V_{CC} = +5.0\text{V}$ $C_{L} = 50 \text{ pF}$		$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	2.4	3.7	5.0	2.0	7.0	2.4	6.0	
t <sub>PHL</sub>	$A_n, B_n, C_n, D_n \text{ to } \overline{O}_n$	1.5	3.2	4.3	1.5	6.5	1.5	5.3	ns



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